



RH1086M

0.5A and 1.5A Low Dropout Positive Adjustable Regulators

DESCRIPTION

The RH1086M positive adjustable regulator is designed to provide 0.5A for the H package and 1.5A for the K package with higher efficiency than currently available devices. All internal circuitry is designed to operate down to 1V input-to-output differential and the dropout voltage is fully specified as a function of load current. Dropout is guaranteed at a maximum of 1.5V at maximum output current, decreasing at lower load currents. On-chip trimming adjusts the output voltage to 1%. Current limit is also trimmed, minimizing the stress on both the regulator and power source circuitry under overload conditions.

The RH1086M is pin compatible with older 3-terminal regulators. A 10 μ F output capacitor is required on this new device. However, this is usually included in most regulator designs.

The wafer lots are processed to Linear Technology Corporation's in-house Class S flow-to-yield circuits usable in stringent military applications.

ABSOLUTE MAXIMUM RATINGS

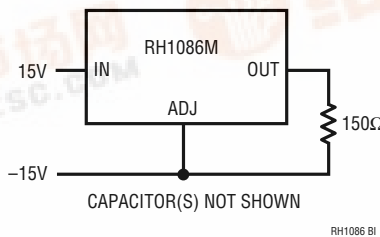
Power Dissipation	Internally Limited
Input-to-Output Voltage Differential	25V
Operating Junction Temperature Range	
Control Section	-55°C to 150°C
Power Transistor	-55°C to 200°C
Storage Temperature Range	-65°C to 150°C
Lead Temperature (Soldering, 10 sec)	300°C

PRECONDITIONING

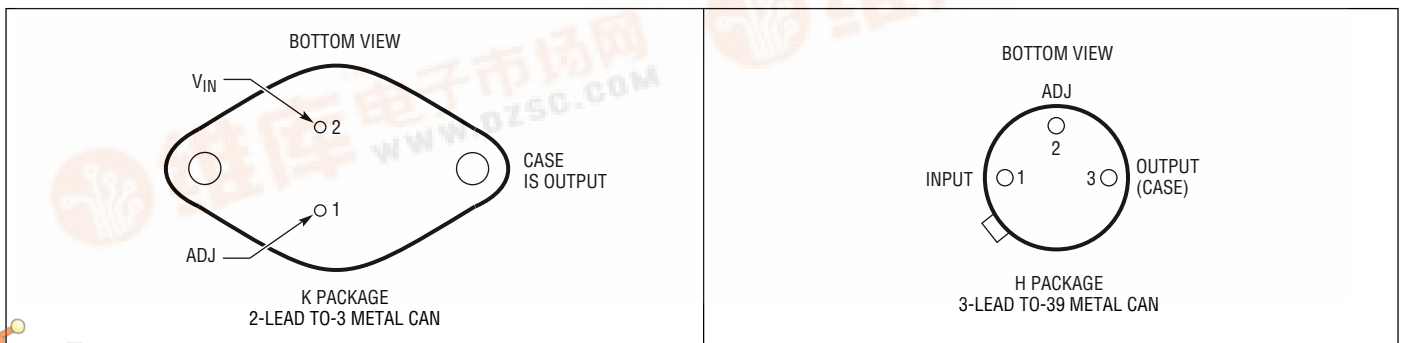
100% Thermal Limit Burn-In

Δ , LTC and LT are registered trademarks of Linear Technology Corporation.

BURN-IN CIRCUIT



PACKAGE INFORMATION



Note: For ordering information contact LTC.



TABLE 1: ELECTRICAL CHARACTERISTICS (Preirradiation)

PARAMETER	CONDITIONS	NOTES	T _A = 25°C			SUB-GROUP	-55°C ≤ T _A ≤ 125°C			SUB-GROUP	UNITS
			MIN	TYP	MAX		MIN	TYP	MAX		
Reference Voltage	I _{OUT} = 10mA, (V _{IN} - V _{OUT}) = 3V (K)		1.238	1.262		1					V
	10mA ≤ I _{OUT} ≤ I _{FULL LOAD} , 1.5V ≤ (V _{IN} - V _{OUT}) ≤ 15V	5	1.225	1.270			1.225	1.270	2,3		V
Line Regulation	I _{OUT} = 10mA, 1.5V ≤ (V _{IN} - V _{OUT}) ≤ 15V	1,2		0.2		1		0.2	2,3		%
Load Regulation	(V _{IN} - V _{OUT}) = 3V, 10mA ≤ I _{OUT} ≤ I _{FULL LOAD}	1,2,5		0.3		1		0.4	2,3		%
Dropout Voltage	ΔV _{REF} = 1%, I _{OUT} = 1.5A (K) ΔV _{REF} = 1%, I _{OUT} = 0.5A (H)	3		1.5		1		1.5	2,3		V
Current Limit	(V _{IN} - V _{OUT}) = 5V (K)		1.5			1	1.5		2,3		A
	(V _{IN} - V _{OUT}) = 5V (H)		0.5			1	0.5		2,3		A
	(V _{IN} - V _{OUT}) = 25V (K)		0.05			1	0.05		2,3		A
	(V _{IN} - V _{OUT}) = 25V (H)		0.020			1	0.020		2,3		A
Minimum Load Current	(V _{IN} - V _{OUT}) = 25V			10		1		10	2,3		mA
Thermal Regulation	30ms Pulse			0.04		4					%/W
Ripple Rejection	f = 120Hz, C _{ADJ} = 25μF, C _{OUT} = 25μF Tantalum, I _{OUT} = I _{FULL LOAD} (V _{IN} - V _{OUT}) = 3V	5	60			4	60		5,6		dB
Adjust Pin Current				55 120				120	2,3		μA
Adjust Pin Current Change	10mA ≤ I _{OUT} ≤ I _{FULL LOAD} , 1.5V ≤ (V _{IN} - V _{OUT}) ≤ 15V	5		5		1		5	2,3		μA
Temperature Stability				0.5				0.5			%
Long Term Stability	T _A = 125°C, 1000 Hours	4		0.3							%
RMS Output Noise (% of V _{OUT})	10Hz ≤ f ≤ 10kHz			0.003							%
Thermal Resistance Junction-to-Case	Control Circuitry (K)	4		1.7							°C/W
	Control Circuitry (H)	4		15.0							°C/W
	Power Transistor (K)	4		4.0							°C/W
	Power Transistor (H)	4		20.0							°C/W

Total Dose Bias Circuit

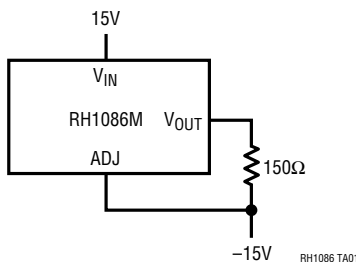


TABLE 1A: ELECTRICAL CHARACTERISTICS (Postirradiation) $T_A = 25^\circ\text{C}$ unless otherwise noted.

PARAMETER	CONDITIONS	10KRAD(Si)		20KRAD(Si)		50KRAD(Si)		100KRAD(Si)		200KRAD(Si)		UNITS
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
Reference Voltage (Note 5)	$I_{OUT} = 10\text{mA}$ ($V_{IN} - V_{OUT} = 3\text{V}$ (K))	1.234	1.258	1.230	1.257	1.225	1.253	1.220	1.247	1.205	1.241	V
	$10\text{mA} \leq I_{OUT} \leq I_{FULL\ LOAD}$ $1.5\text{V} \leq (V_{IN} - V_{OUT}) \leq 15\text{V}$	1.220	1.275	1.219	1.275	1.215	1.275	1.210	1.275	1.20	1.275	V
Line Regulation (Notes 1, 2)	$I_{OUT} = 10\text{mA}$ $1.5\text{V} \leq (V_{IN} - V_{OUT}) \leq 15\text{V}$		0.2		0.21		0.23		0.25		0.3	%
Load Regulation (Notes 1, 2, 5)	$(V_{IN} - V_{OUT}) = 3\text{V}$ $10\text{mA} \leq I_{OUT} \leq I_{FULL\ LOAD}$		0.3		0.3		0.3		0.3		0.3	%
Dropout Voltage (Note 3)	$\Delta V_{REF} = 1\%$, $I_{OUT} = 1.5\text{A}$ (K) $\Delta V_{REF} = 1\%$, $I_{OUT} = 0.5\text{A}$ (H)		1.5		1.51		1.52		1.55		1.575	V
Current Limit	$(V_{IN} - V_{OUT}) = 5\text{V}$ (K)	1.5		1.5		1.5		1.5		1.5		A
	$(V_{IN} - V_{OUT}) = 25\text{V}$ (K)	0.05		0.049		0.048		0.047		0.045		A
	$(V_{IN} - V_{OUT}) = 5\text{V}$ (H)	0.5		0.5		0.5		0.5		0.5		A
	$(V_{IN} - V_{OUT}) = 25\text{V}$ (H)	0.020		0.019		0.019		0.018		0.017		A
Minimum Load Current	$(V_{IN} - V_{OUT}) = 25\text{V}$		10		10		10		10		10	mA
Adjust Pin Current			120		120		120		120		120	μA
Adjust Pin Current Change (Note 5)	$10\text{mA} \leq I_{OUT} \leq I_{FULL\ LOAD}$ $1.5\text{V} \leq (V_{IN} - V_{OUT}) \leq 15\text{V}$		5		5		5		5		5	μA

Note 1: See thermal regulation specifications for changes in output voltage due to heating effects. Line and load regulation are measured at a constant junction temperature by low duty cycle pulse testing.

Note 2: Line and load regulation are guaranteed up to the maximum power dissipation of 15W for RH1086MK and 3W for the RH1086MH. Power dissipation is determined by the input/output differential voltage and the output current. Guaranteed maximum power dissipation will not be available over the full input/output voltage range.

Note 3: Dropout voltage is specified over the full output current range of the device. Test points and limits are shown on the Dropout Voltage curve in the LT[®]1086 data sheet.

Note 4: Guaranteed by design, characterization, or correlation to other tested parameters.

Note 5: $I_{FULL\ LOAD}$ is defined in the Current Limit curves in the standard data sheet. For compliance with 883 revision C current density specifications, the RH1086MK is derated to 1A.

TABLE 2: ELECTRICAL TEST REQUIREMENTS

MIL-STD-883 TEST REQUIREMENTS	SUBGROUP
Final Electrical Test Requirements (Method 5004)	1*,2,3,4,5,6
Group A Test Requirements (Method 5005)	1,2,3,4,5,6
Group C and D End Point Electrical Parameters (Method 5005)	1

* PDA Applies to subgroup 1. See PDA Test Notes.

PDA Test Notes

The PDA is specified as 5% based on failures from group A, subgroup 1, tests after cooldown as the final electrical test in accordance with method 5004 of MIL-STD-883 Class B. The verified failures of group A, subgroup 1, after burn-in divided by the total number of devices submitted for burn-in in that lot shall be used to determine the percent for the lot.

Linear Technology Corporation reserves the right to test to tighter limits than those given.

TYPICAL PERFORMANCE CHARACTERISTICS

